

TEST REPORT

Report No. A-053-11-V		Date of Issue: 5 March 2012
Department of	of Defense Interface Standard Military Standard 46	61 □E ⊠F
The results of this report should	t the device was tested according to the requirement to the construed to imply compliance of device all by the documents, this report should not be copi	es other than the sample tested.
1. Applicant		
Company Name	: IT Products Business Unit, Business solutions AVC networks company, Panasonic Corporation	4 *
Mailing Address	: 1-10-12 Yagumo-higashi-machi, Moriguchi Ci	ty, Osaka 570-0021, Japan
2. Identification of Tested De	vice	
Device Name	: Personal Computer	
Model Number	: CF-19	
Serial Number	: 1EKSA00552	
Trade Name	: Panasonic	
Type of Test	: Product Validation Design Validation	
Test Plan Number	: KEC-G111_A-053-11-V Date:2012-3-5	
Modification of Test Plan : ⊠ No ☐ Yes (refer to deviation information in this report)		
3. Test Items and Procedure		
CE101, Conducted Emissi	ons, Power Leads	⊠ Pass ☐ Fail ☐ N/A
CE102, Conducted Emissi	ons, Power Leads	⊠ Pass ☐ Fail ☐ N/A
CS101, Conducted Suscep		☐ Pass ☐ Fail ☐ N/A
	otibility, Transients, Power Leads	☐ Pass ☐ Fail ☐ N/A (*3)
	tibility, Bulk Cable Injection	⊠ Pass □ Fail □ N/A
	otibility, Bulk Cable Injection, Impulse Excitation	⊠ Pass □ Fail □ N/A
CS116, Conducted Susceptibility, Damped Sinusoidal Transients,		
Cables and Power Leads		
RE101, Radiated Emission	ns, Magnetic Field	⊠ Pass ☐ Fail ☐ N/A
RE102, Radiated Emission		☐ Pass ☐ Fail ☐ N/A
RS101, Radiated Suscepti		☐ Pass ☐ Fail ☐ N/A
RS103, Radiated Suscepti		⊠ Pass ☐ Fail ☐ N/A
Refer the below reason(s) with respect to the decision and justification not to test.		
(*1) DUT Specification (*2) Request of Applicant (*3) According to Test Plan		
KEC Electronic Industry Deve	lopment Center Testing Division	
	oraku-gun, Kyoto 619-0237 Japan	
Test Engineer(s)		
,	1.	
A. Sugniar	o Holomatro	
Hisanori Sugimoto Hironori Okamoto		
JAB T. Masaoka		
Resting Restaution Approved by Kenji Masaoka / Group Manager		